

EV372453383

Inventor: F. Gonzalez et. al.

Title: Methods of Forming Semiconductor Circuitry

Assignee: Micron Technology, Inc.

INFORMATION DISCLOSURE STATEMENT

PURSUANT TO 37 C.F.R. §§1.56, 1.97 AND 1.98

In compliance with 37 C.F.R. §§1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449.


The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional of co-pending application Serial No. 09/989,931 filed November 21, 2001. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). No admission is made regarding whether all the submitted references are prior art.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated: MARCH 31, 2004

Attorney:


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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2536		priority SERIAL NO. 09/989,931	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				priority FILING DATE 11/21/01		priority GROUP 2815	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,462,381 B1	10/02	Beebe et al.			
	AB	5,999,675	12/99	Sugiyama			
	AC	6,555,891 B1	04/03	Furukawa et al.			
	AD	5,891,769	04/99	Liaw et al.			
	AE	6,653,714 B2	11/03	Matsuno et al.			
	AF	6,544,854 B1	04/03	Puchner et al.			
	AG	6,620,671 B1	09/03	Wang et al.			
	AH	6,358,806 B1	03/02	Puchner			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AI	JP 11-177122 A	07/99	Sugiyama			
	AJ	JP 10270746 A	10/98	Sugiyama			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK						
	AL						
	AM						
	AN						
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EXAMINER				DATE CONSIDERED			
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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,759,908	06/98	Steckl			
	AB	2002/0019105 A1	02/02	Hattorie et al.			
	AC	2003/0162586 A1	04/03	Wallace et al.			
	AD	2002/0182423 A1	12/02	Chu et al.			
	AE	2002/0086557 A1	07/02	Matsumura et al.			
	AF						
	AG						
	AH						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AI						
	AJ						
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